Abstracts

An Improved Computational Method for Noise Parameter Measurement

M. Mitama and H. Katoh. "An Improved Computational Method for Noise Parameter Measurement." 1979 Transactions on Microwave Theory and Techniques 27.6 (Jun. 1979 [T-MTT]): 612-615.

Conventional methods for noise parameter measurement for linear noisy two-ports have been improved by introducing a computational method for evaluating measured admittance errors. Derivation and comparison with a conventional method are given. Noise parameters of a packaged 0.5-mu m gate-length GaAs MESFET (NE38806) were successfully measured using the proposed technique.

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